

Notice of References Cited		Application/Control No.	Applicant(s)/Patent Under Reexamination 10/772,422 KIM ET AL.	
		Examiner	Art Unit SHIN-HON CHEN	2131 Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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*	B	US-2002/0015422	02-2002	Inada et al.	370/474
	C	US-			
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FOREIGN PATENT DOCUMENTS

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NON-PATENT DOCUMENTS

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